

Welcome to [E-XFL.COM](#)**Understanding [Embedded - CPLDs \(Complex Programmable Logic Devices\)](#)**

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

Applications of Embedded - CPLDs**Details**

Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	15 ns
Voltage Supply - Internal	3V ~ 3.6V
Number of Logic Elements/Blocks	-
Number of Macrocells	128
Number of Gates	-
Number of I/O	74
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/m5lv-128-74-15vi

**Select devices have been discontinued.
See Ordering Information section for product status.**

Table 1. MACH 5 Device Features¹

Feature	M5-128/1 M5LV-128		M5-192/1		M5-256/1 M5LV-256		M5-320 M5LV-320		M5-384 M5LV-384		M5-512 M5LV-512	
Supply Voltage (V)	5	3.3	5	5	3.3	5	3.3	5	3.3	5	3.3	
Macrocells	128	128	192	256	256	320	320	384	384	512	512	
Maximum User I/O Pins	120	120	120	160	160	192	160	160	160	256	256	
t _{PD} (ns)	5.5	5.5	5.5	5.5	5.5	6.5	6.5	6.5	6.5	6.5	6.5	
t _{SS} (ns)	3.0	3.0	3.0	3.0	3.0	3.0	3.0	3.0	3.0	3.0	3.0	
t _{COS} (ns)	4.5	4.5	4.5	4.5	4.5	5.0	5.0	5.0	5.0	5.0	5.0	
f _{CNT} (MHz)	182	182	182	182	182	167	167	167	167	167	167	
Typical Static Power (mA)	35	35	45	55	55	70	70	75	75	100	100	
IEEE 1149.1 Boundary Scan Compliant	Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes	
PCI-Compliant	Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes	

Note:

1. "M5-xxxx" is for 5-V devices. "M5LV-xxxx" is for 3.3-V devices.

GENERAL DESCRIPTION

The MACH® 5 family consists of a broad range of high-density and high-I/O Complex Programmable Logic Devices (CPLDs). The fifth-generation MACH architecture yields fast speeds at high CPLD densities, low power, and supports additional features such as in-system programmability, Boundary Scan testability, and advanced clocking options (Table 1). The MACH 5 family offers 5-V (M5-xxx) and 3.3-V (M5LV-xxx) operation.

Manufactured in state-of-the-art ISO 9000 qualified fabrication facilities on E²CMOS process technologies, MACH 5 devices are available with pin-to-pin delays as fast as 5.5 ns (Table 2). The 5.5, 6.5, 7.5, 10, and 12-ns devices are compliant with the *PCI Local Bus Specification*.

Table 2. MACH 5 Speed Grades

Device	Speed Grade ¹						
	-5	-6	-7	-10	-12	-15	-20
M5-128 ²			C	C, I	C, I	C, I	I
M5-128/1	C		C, I	C, I	C, I	C, I	I
M5LV-128	C		C,I	C, I	C, I	I	
M5-192/1	C		C, I	C, I	C, I	C, I	I
M5-256 ²			C	C, I	C, I	C, I	I
M5-256/1	C		C, I	C, I	C, I	C, I	I
M5LV-256	C		C, I	C, I	C, I	I	
M5-320		C	C, I	C, I	C, I	C, I	I
M5LV-320		C	C, I	C, I	C, I	C, I	I
M5-384		C	C, I	C, I	C, I	C, I	I
M5LV-384		C	C, I	C, I	C, I	C, I	I
M5-512		C	C, I	C, I	C, I	C, I	I
M5LV-512		C	C, I	C, I	C, I	C, I	I

Note:

1. C = Commercial grade, I = Industrial grade
2. /1 version recommended for new designs

With Lattice's unique hierarchical architecture, the MACH 5 family provides densities up to 512 macrocells to support full system logic integration. Extensive routing resources ensure pinout retention as well as high utilization. It is ideal for PAL® block device integration and a wide range of other applications including high-speed computing, low-power applications, communications, and embedded control. At each macrocell density point, Lattice offers several I/O and package options to meet a wide range of design needs (Table 3).

Table 3. MACH 5 Package and I/O Options¹

Supply Voltage	M5-128/1 M5LV-128		M5-256/1 M5LV-256		M5-320 M5LV-320		M5-384 M5LV-384		M5-512 M5LV-512		
	5	3.3	5	5	3.3	5	3.3	5	3.3	5	3.3
100-pin TQFP	68	68, 74	68	68	68*, 74						
100-pin PQFP	68	68*	68*	68*	68						
144-pin TQFP		104			104						
144-pin PQFP	104	104*	104*	104*	104*						
160-pin PQFP	120	120	120	120	120	120*	120	120*	120	120*	120
208-pin PQFP				160	160	160	160	160	160	160	160
240-pin PQFP						184*	184*	184*	184*	184*	184*
256-ball BGA						192	192*	192*	192*	192*	192*
352-ball BGA										256	256

Note:

1. The I/O options indicated with a "*" are obsolete, please contact factory for more information.

Advanced power management options allow designers to incrementally reduce power while maintaining the level of performance needed for today's complex designs. I/O safety features allow for mixed-voltage design,

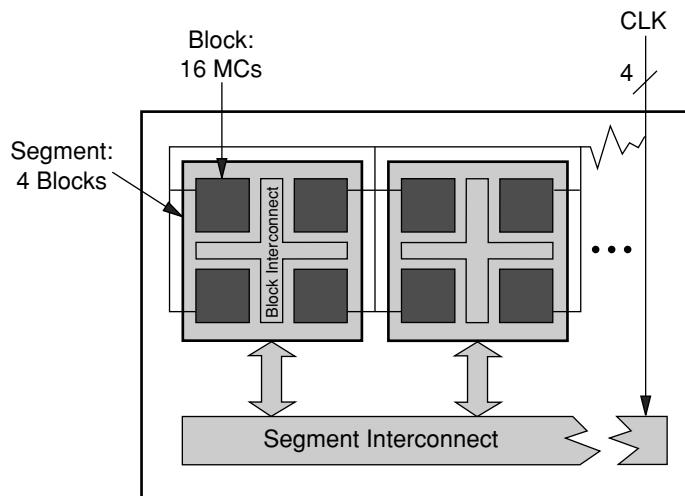
Select devices have been discontinued.
See Ordering Information section for product status.

Select devices have been discontinued.
See Ordering Information section for product status.

and both the 3.3-V and the 5-V device versions are in-system programmable through an IEEE 1149.1 Test Access Port (TAP) interface.

FUNCTIONAL DESCRIPTION

The MACH 5 architecture consists of PAL blocks connected by two levels of interconnect. The **block interconnect** provides routing among 4 PAL blocks. This grouping of PAL blocks joined by the block interconnect is called a **segment**. The second level of interconnect, the **segment interconnect**, ties all of the segments together. The only logic difference between any two MACH 5 devices is the number of segments. Therefore, once a designer is familiar with one device, consistent performance can be expected across the entire family. All devices have four clock pins available which can also be used as logic inputs.



20446G-001

Figure 1. MACH 5 Block Diagram

The MACH 5 PAL blocks consist of the elements listed below (Figure 2). While each PAL block resembles an independent PAL device, it has superior control and logic generation capabilities.

- ◆ I/O cells
- ◆ Product-term array and Logic Allocator
- ◆ Macrocells
- ◆ Register control generator
- ◆ Output enable generator

I/O Cells

The I/Os associated with each PAL block have a path directly back to that PAL block called **local feedback**. If the I/O is used in another PAL block, the **interconnect feeder** assigns a **block interconnect** line to that signal. The interconnect feeder acts as an input switch matrix. The block and segment interconnects provide connections between any two signals in a device. The **block feeder** assigns block interconnect lines and local feedback lines to the PAL block inputs.

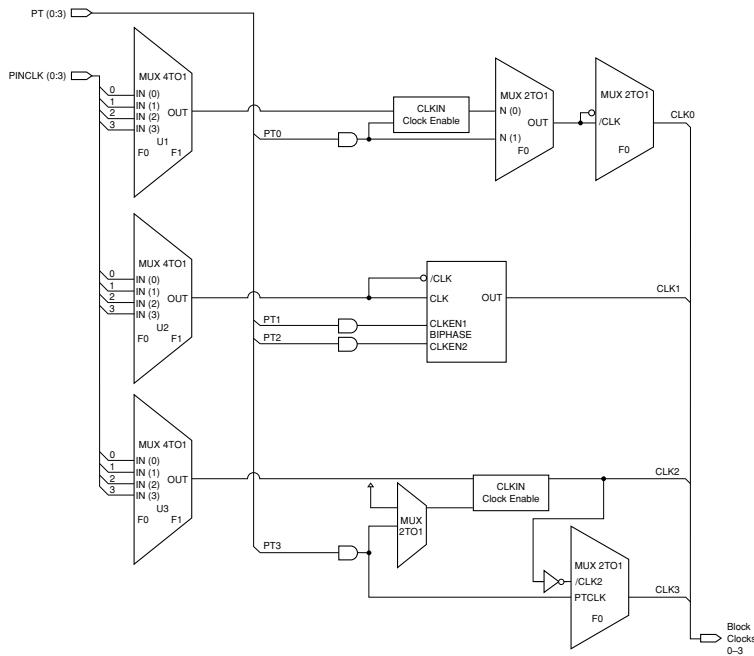
- ◆ Global clock (0, 1, 2, or 3) with positive and negative edge clock enable (biphase)

Clock Line 2 Options

- ◆ Global clock (0, 1, 2, or 3) with clock enable

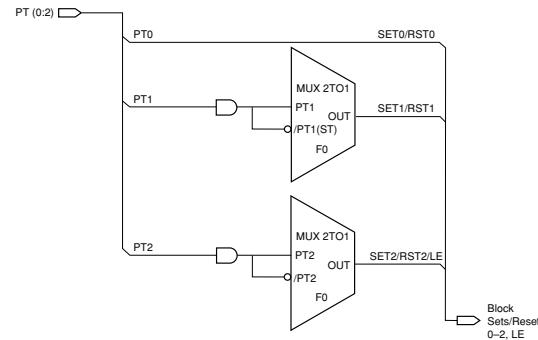
Clock Line 3 Options

- ◆ Complement of clock line 2 (same clock enable)
- ◆ Product-term clock (if clock line 2 does not use clock enable)



20446G-004

Figure 4. Clock Generator



20446G-005

Figure 5. Set/Reset Generator

The set/reset generation portion of the control generator (Figure 5) creates three set/reset lines for the PAL block. Each macrocell can choose one of these three lines or choose no set/reset at all. All three lines can be configured for product term set/reset and two of the three lines can be configured as sum term set/reset and one of the lines can be configured as product-term or sum-term latch enable. While the set/reset signals are generated in the control generator, whether that signal sets or resets a flip-flop is determined within the individual macrocell. The same signal can set one flip-flop and reset another. PT2 or /PT2 can also be used as a latch enable for macrocells configured as latches.

Select devices have been discontinued.
See Ordering Information section for product status.

MACH 5 TIMING MODEL

The primary focus of the MACH 5 timing model is to accurately represent the timing in a MACH 5 device, and at the same time, be easy to understand. This model accurately describes all combinatorial and registered paths through the device, making a distinction between **internal feedback** and **external feedback**. A signal uses internal feedback when it is fed back into the switch matrix or block without having to go through the output buffer. The input register specifications are also reported as internal feedback. When a signal is fed back into the switch matrix after having gone through the output buffer, it is using external feedback.

The parameter, t_{BUF} is defined as the time it takes to go through the output buffer to the I/O pad. If a signal goes to the internal feedback rather than to the I/O pad, the parameter designator is followed by an “i”. By adding t_{BUF} to this internal parameter, the external parameter is derived. For example, $t_{PD} = t_{PDI} + t_{BUF}$. A diagram representing the modularized MACH 5 timing model is shown in Figure 7. Refer to the Technical Note entitled *MACH 5 Timing and High Speed Design* for a more detailed discussion about the timing parameters.

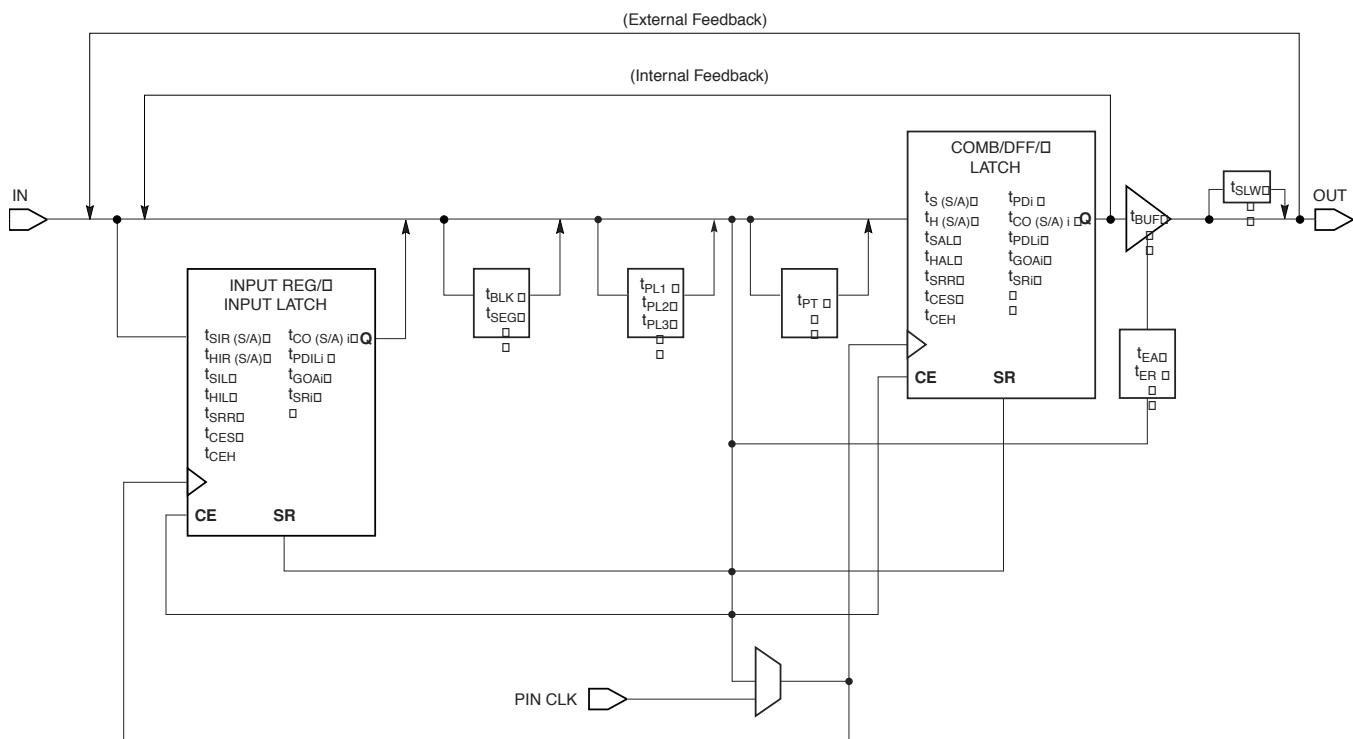


Figure 7. MACH 5 Timing Model

20446G-014

**Select devices have been discontinued.
See Ordering Information section for product status.**

See Ordering Information section for product status.

Select devices have been discontinued.

MULTIPLE I/O AND DENSITY OPTIONS

The MACH 5 family offers six macrocell densities in a number of I/O options. This allows designers to choose a device close to their logic density and I/O requirements, thus minimizing costs. For the same package type, every density has the same pin-out. With proper design considerations, a design can be moved to a higher or lower density part as required.

IEEE 1149.1 - COMPLIANT BOUNDARY SCAN TESTABILITY

Most MACH 5 devices have boundary scan registers and are compliant to the IEEE 1149.1 standard. This allows functional testing of the circuit board on which the device is mounted through a serial scan path that can access all critical logic nodes. Internal registers are linked internally, allowing test data to be shifted in and loaded directly onto test nodes, or test node data to be captured and shifted out for verification. In addition, these devices can be linked into a board-level serial scan path for more complete board-level testing.

IEEE 1149.1 - COMPLIANT IN-SYSTEM PROGRAMMING

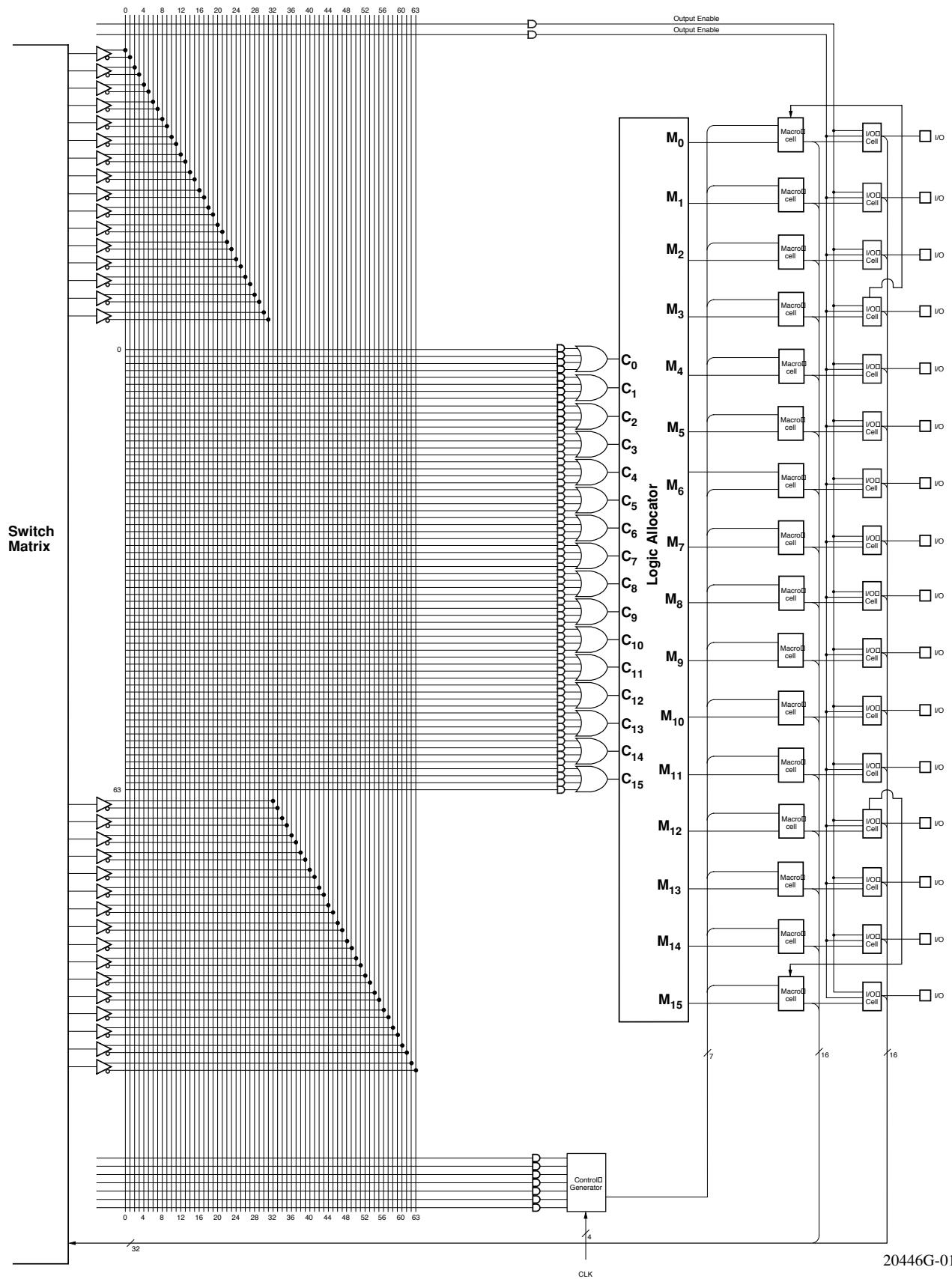
Programming devices in-system provides a number of significant benefits including: rapid prototyping, lower inventory levels, higher quality, and the ability to make in-field modifications. All MACH 5 devices provide in-system programming (ISP) capability through their IEEE 1149.1-compliant Boundary Scan Test Access Port. By using the IEEE 1149.1-compliant Boundary Scan Test Access Port as the communication interface through which ISP is achieved, customers get the benefit of a standard, well-defined interface.

MACH 5 devices can be programmed across the commercial temperature and voltage range. The PC-based LatticePRO software facilitates in-system programming of MACH 5 devices. LatticePRO software takes the JEDEC file output produced by design implementation software, along with information about the Boundary Scan chain, and creates a set of vectors that are used to drive the Boundary Scan chain. LatticePRO software can use these vectors to drive a Boundary Scan chain via the parallel port of a PC. Alternatively, LatticePRO software can output files in formats understood by common automated test equipment. This equipment can then be used to program MACH 5 devices during the testing of a circuit board.

PCI COMPLIANT

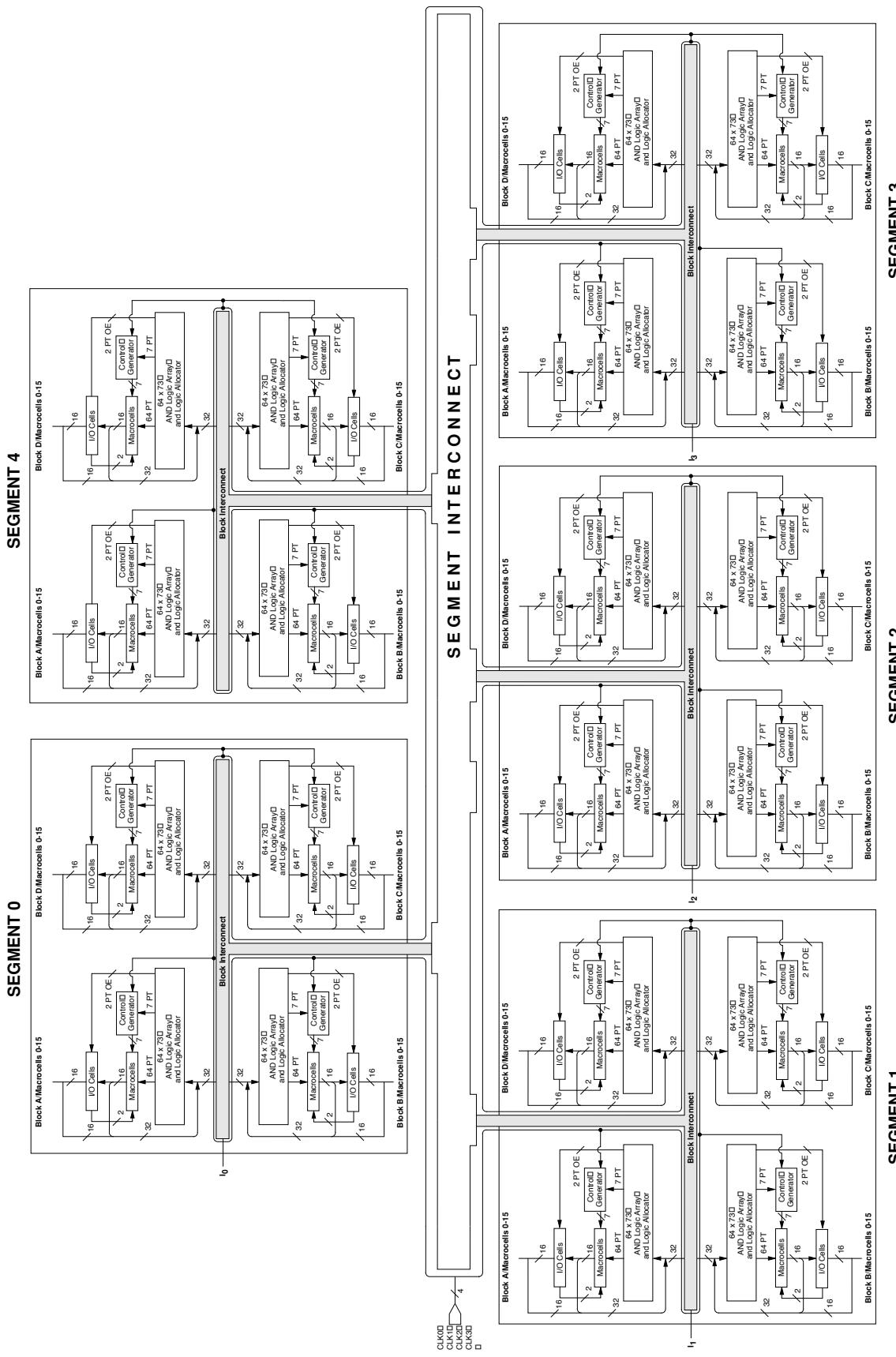
MACH 5 devices in the -5/-6/-7/-10/-12 speed grades are compliant with the *PCI Local Bus Specification* version 2.1, published by the PCI Special Interest Group (SIG). The 5-V devices are fully PCI-compliant. The 3.3-V devices are mostly compliant but do not meet the PCI condition to clamp the inputs as they rise above V_{CC} because of their 5-V input tolerant feature. MACH 5 devices provide the speed, drive, density, output enables and I/Os for the most complex PCI designs.

MACH 5 PAL BLOCK



Select devices have been discontinued.
See Ordering Information section for product status.

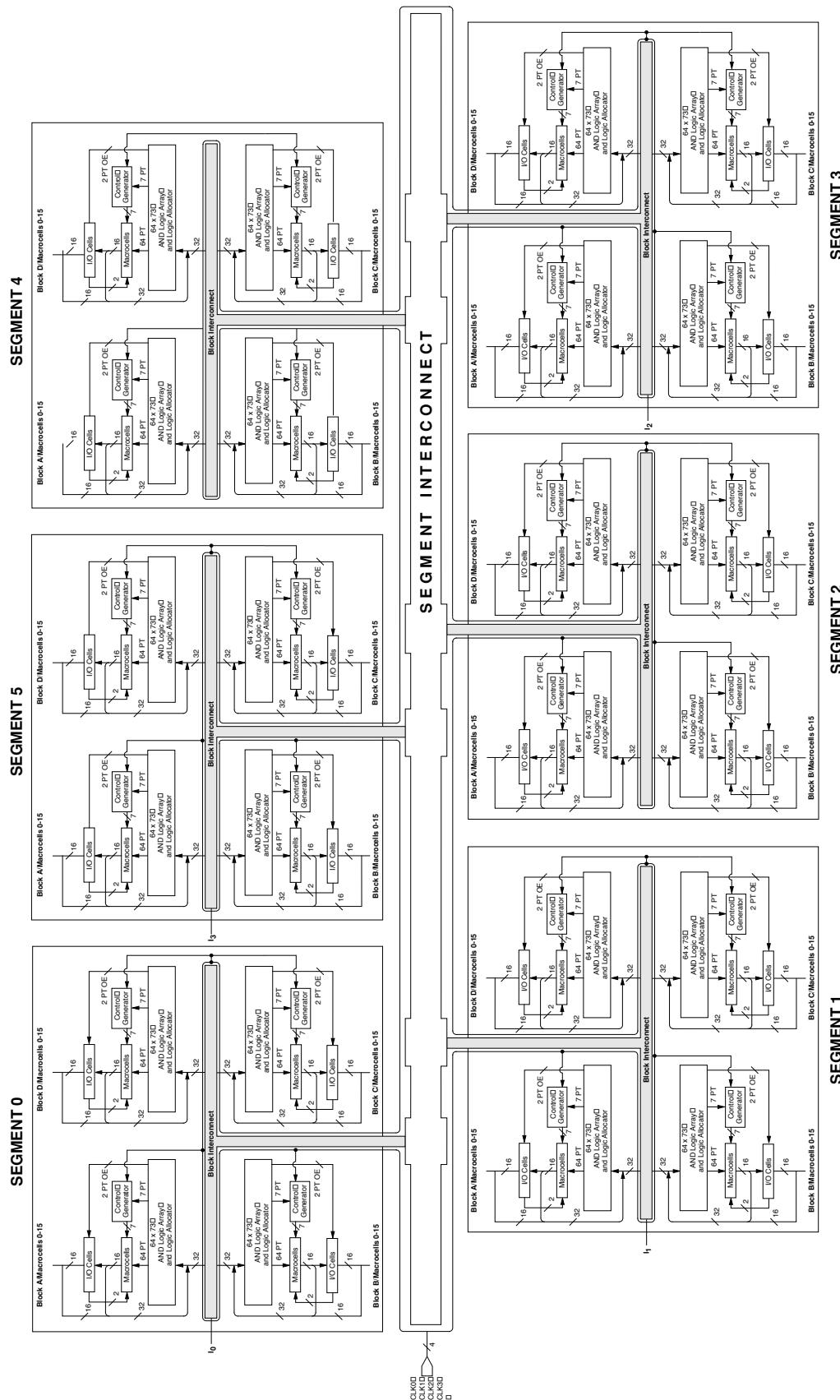
BLOCK DIAGRAM — M5(LV)-320/XXX



Select devices have been discontinued.
See Ordering Information section for product status.

Select devices have been discontinued.
See Ordering Information section for product status.

BLOCK DIAGRAM — M5(LV)-384/XXX



20446G-011

Select devices have been discontinued.
See Ordering Information section for product status.

M5(LV) TIMING PARAMETERS OVER OPERATING RANGES¹ (CONTINUED)

	-5		-6		-7		-10		-12		-15		-20		Unit	
	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
Power Delays:																
t _{PL1}	Power level 1 delay (Note 2)		4.0 (5.0)		4.0		4.0 (5.0)		4.0 (5.0)		4.0 (5.0)		4.0 (5.0)		4.0 (5.0)	ns
t _{PL2}	Power level 2 delay (Note 2)		6.0 (9.0)		6.0		6.0 (9.0)		6.0 (9.0)		6.0 (9.0)		6.0 (9.0)		6.0 (9.0)	ns
t _{PL3}	Power level 3 delay (Note 2)		9.0 (17.5)		9.0		9.0 (17.5)		9.0 (17.5)		9.0 (17.5)		9.0 (17.5)		9.0 (17.5)	ns
Additional Cluster Delay:																
t _{PT}	Product term cluster delay		0.3		0.3		0.3		0.3		0.3		0.3		0.3	ns
Interconnect Delays:																
t _{BLK}	Block interconnect delay		1.5		1.5		1.5		2.0		2.0		2.0		2.0	ns
t _{SEG}	Segment interconnect delay		4.5		4.5		5.0		6.0		6.0		6.0		6.0	ns
Reset and Preset Delays:																
t _{SRI}	Asynchronous reset or preset to internal register output		6.0		8.0		8.0		10.0		12.0		14.0		16.0	ns
t _{SR}	Asynchronous reset or preset to register output		8.0		10.0		10.0		12.0		14.0		16.0		18.0	ns
t _{SRR}	Reset and set register recovery time	5.5		7.5		7.5		8.0		9.0		10.0		11.0		ns
t _{SRW}	Asynchronous reset or preset width	3.0		4.0		4.0		5.0		6.0		7.0		8.0		ns
Clock Enable Delays:																
t _{CES}	Clock enable setup time	4.0		5.0		5.0		6.0		7.0		7.0		8.0		ns
t _{CEH}	Clock enable hold time	3.0		4.0		4.0		5.0		6.0		6.0		7.0		ns
Width:																
t _{WLS}	Global clock width low (Note 3)	2.5		3.0		3.0		4.0		5.0		6.0		6.0		ns
t _{WHS}	Global clock width high (Note 3)	2.5		3.0		3.0		4.0		5.0		6.0		6.0		ns
t _{WLA}	Product term clock width low	3.0		4.0		4.0		5.0		6.0		7.0		8.0		ns
t _{WHA}	Product term clock width high	3.0		4.0		4.0		5.0		6.0		7.0		8.0		ns
t _{GWA}	Gate width low (for low transparent) or high (for high transparent)	3.0		4.0		4.0		5.0		6.0		7.0		8.0		ns
t _{WIR}	Input register clock width low or high	3.0		4.0		4.0		5.0		6.0		7.0		8.0		ns

M5(LV) TIMING PARAMETERS OVER OPERATING RANGES¹ (CONTINUED)

	-5		-6		-7		-10		-12		-15		-20		Unit	
	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
Frequency:																
f_{MAX}	External feedback, PAL block level. Min of $1/(t_{WLS} + t_{WHS})$ or $1/(t_{SS} + t_{COS})$	133		125		100		83.3		71.4		55.6		45.5		MHz
	Internal feedback, PAL block level. Min of $1/(t_{WLS} + t_{WHS})$ or $1/(t_{SS} + t_{COS})$	182		167		125		100		83.3		62.5		50.0		MHz
	No feedback PAL block level. Min of $1/(t_{WLS} + t_{WHS})$ or $1/(t_{SS} + t_{HS})$	200		167		167		125		100		83.3		83.3		MHz
f_{MAXA}	External feedback, PAL block level. Min of $1/(t_{WLA} + t_{WHA})$ or $1/(t_{SA} + t_{COA})$	91		91		71.4		58.8		47.6		41.7		35.7		MHz
	Internal feedback, PAL block level. Min of $1/(t_{WLA} + t_{WHA})$ or $1/(t_{SA} + t_{COAi})$	111		111		83.3		66.7		52.6		45.5		38.5		MHz
	No feedback, PAL block level. Min of $1/(t_{WLA} + t_{WHA})$ or $1/(t_{SA} + t_{HA})$	167		125		125		100		83.3		71.4		62.5		MHz
f_{MAXI}	Maximum input register frequency $1/(t_{SIRS} + t_{HIRS})$ or $1/(2 \times t_{WICW})$	167		125		125		100		83.3		71.4		62.5		MHz

Notes:

1. See "MACH Switching Test Circuits" documentation on the Lattice Data Book CD-ROM or Lattice web site.
2. Numbers in parentheses are for M5-128, M5-192, M5-256.
3. If a signal is used as both a clock and a logic array input, then the maximum input frequency applies ($f_{MAX}/2$).

Select devices have been discontinued.
See Ordering Information section for product status.

Select devices have been discontinued.
See Ordering Information section for product status.

CAPACITANCE¹

Parameter Symbol	Parameter Description	Test conditions		Typ	Unit
C_{IN}	I/CLK pin	$V_{IN} = 2.0\text{ V}$	$3.3\text{ V or }5\text{ V}, 25^\circ\text{ C}, 1\text{ MHz}$	12	pF
$C_{I/O}$	I/O pin	$V_{OUT} = 2.0\text{ V}$	$3.3\text{ V or }5\text{ V}, 25^\circ\text{ C}, 1\text{ MHz}$	10	pF

1. These parameters are not 100% tested, but are calculated at initial characterization and at any time the design is modified where these parameters may be affected.

I_{CC} vs. FREQUENCY

These curves represent the typical power consumption for a particular device at system frequency. The selected “typical” pattern is a 16-bit up-down counter. This pattern fills the device and exercises every macrocell. Maximum frequency shown uses internal feedback and a D-type register. Power/Speed are optimized to obtain the highest counter frequency and the lowest power. The highest frequency (LSBs) is placed in common PAL blocks, which are set to high power. The lowest frequency signals (MSBs) are placed in a common PAL block and set to lowest power. For a more detailed discussion about MACH 5 power consumption, refer to the application note entitled *MACH 5 Power* in the Application Notes section on the Lattice Data Book CD-ROM or Lattice web site.

I_{CC} CURVES AT HIGH /LOW POWER MODES

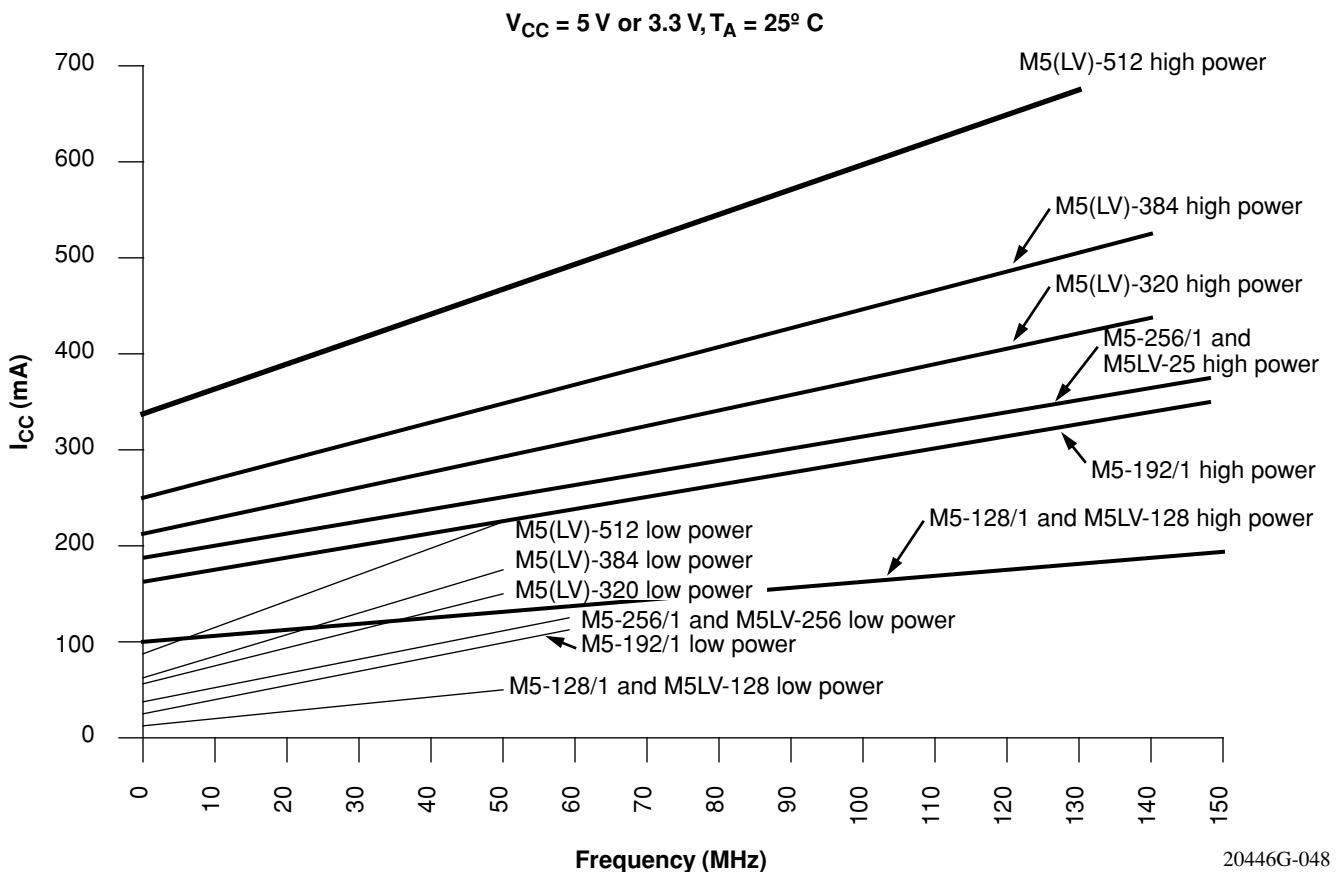


Figure 8. I_{CC} Curves at High/Low Power Modes

20446G-048

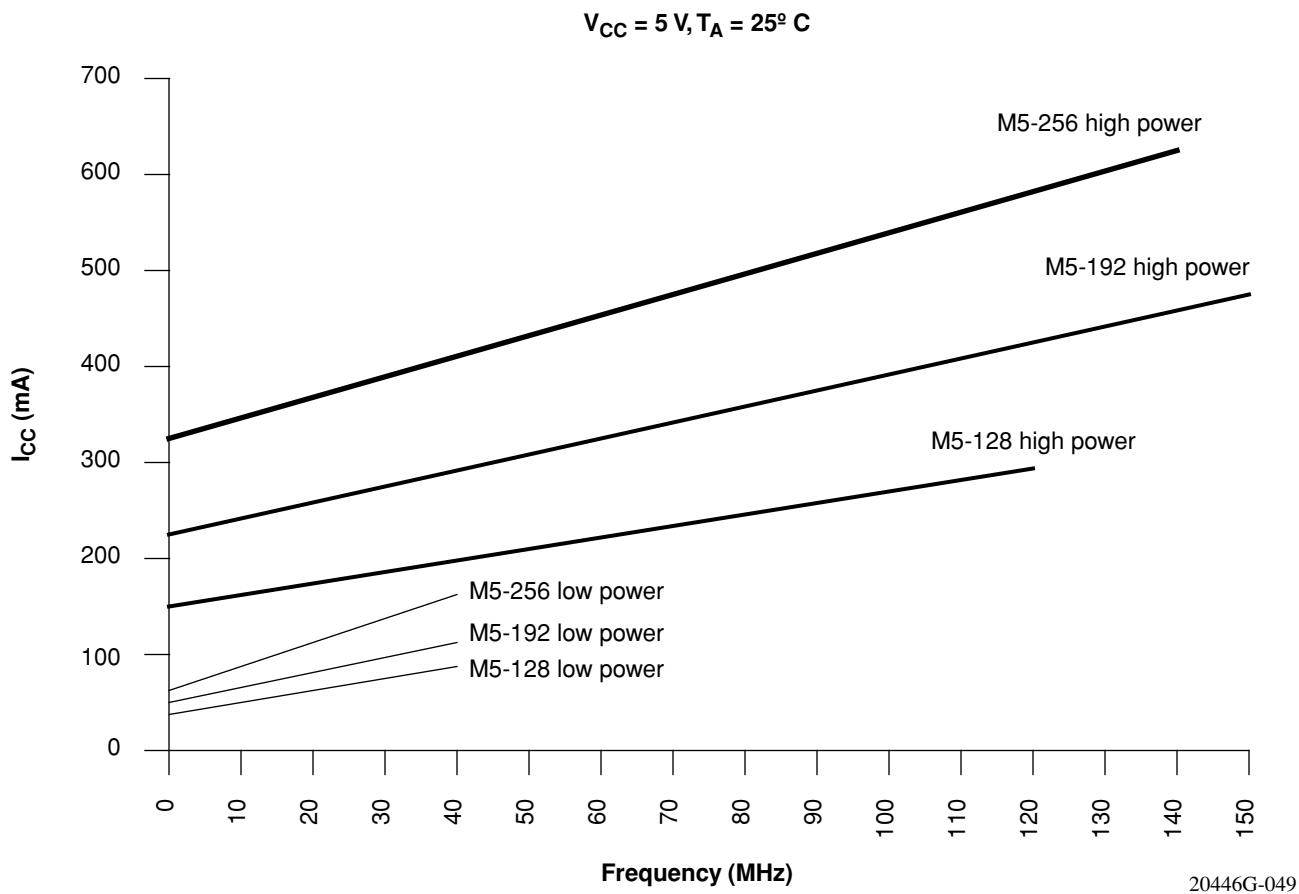


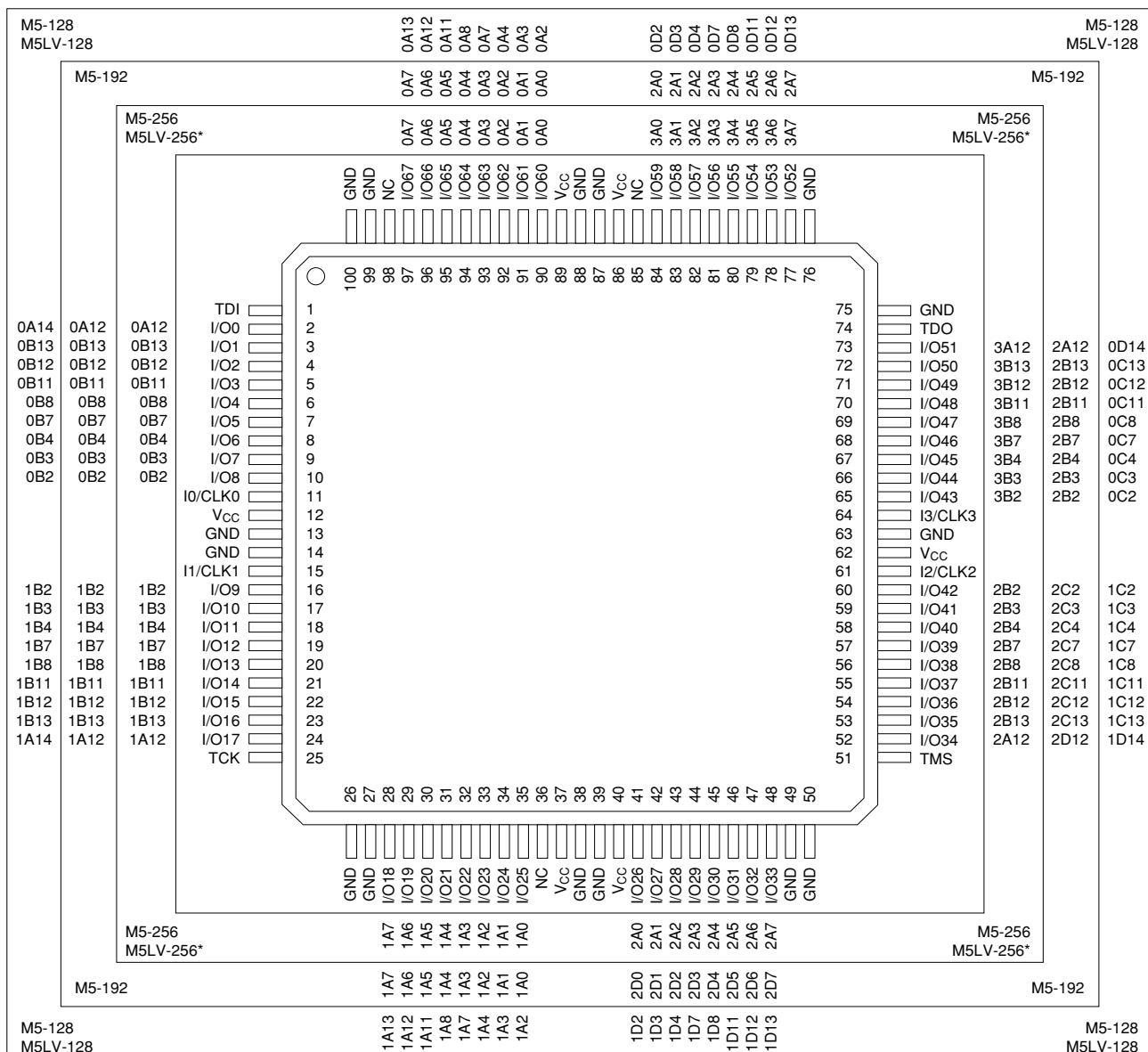
Figure 9. I_{CC} Curves at High/Low Power Modes

Select devices have been discontinued.
See Ordering Information section for product status.

100-PIN TQFP CONNECTION DIAGRAM – 68 I/O

Top View

100-Pin TQFP (68 I/O)



*Package obsolete, contact factory

20446G-017

Pin Designations

CLK ≡ Clock

GND = Ground

GND = Ground

I = Input
I/O = Input/Output

V_{CC} ≡ Supply Voltage

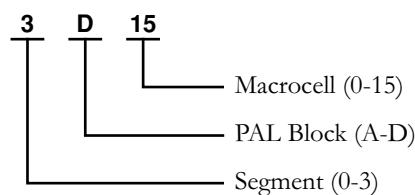
TDI = Test Data In

TDR = Test Data Register

TCK = Test Clock

TDO = Test Data Out

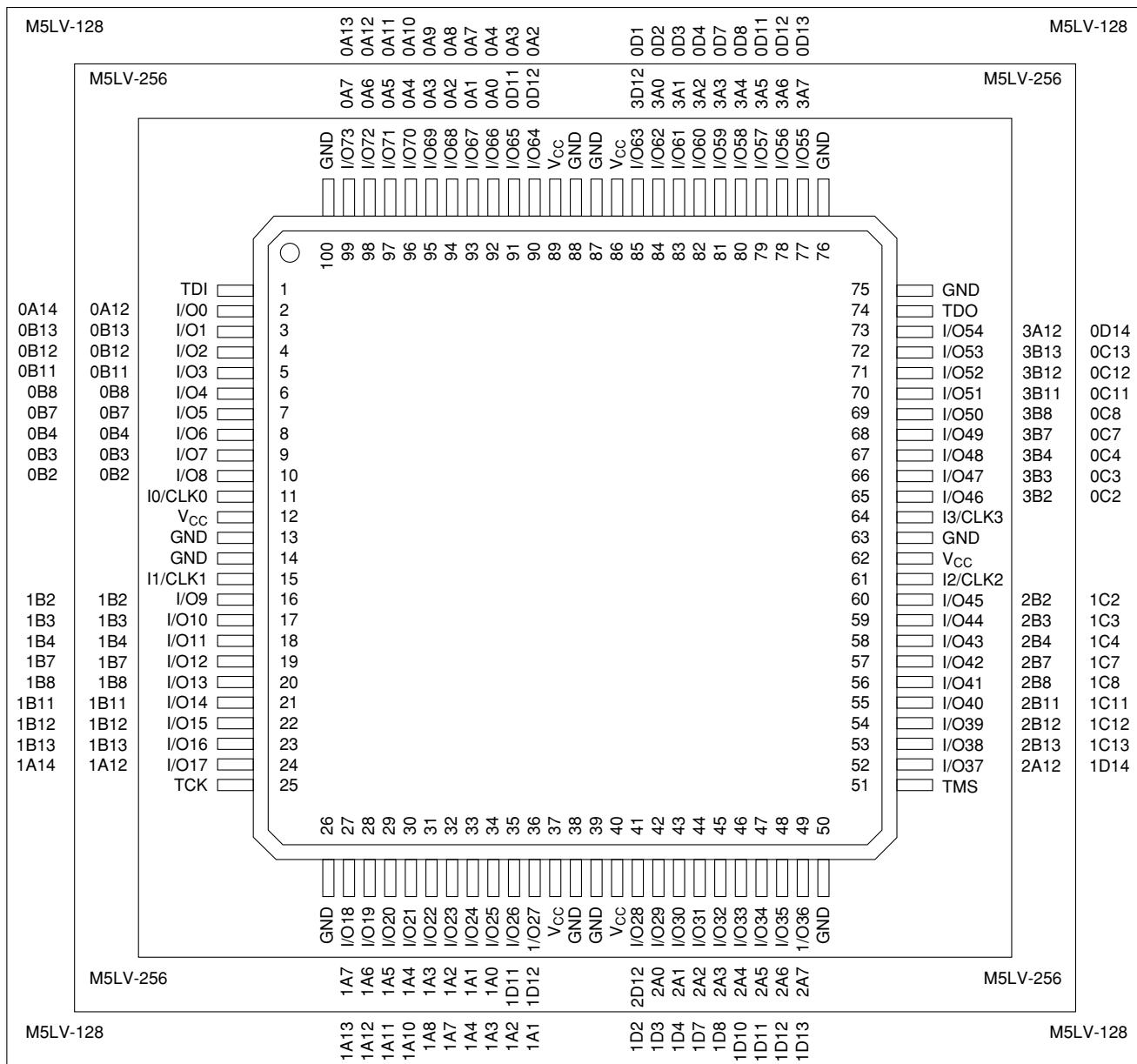
TDO = Test Data Out



100-PIN TQFP CONNECTION DIAGRAM – 74 I/O

Top View

100-Pin TQFP (74 I/O)



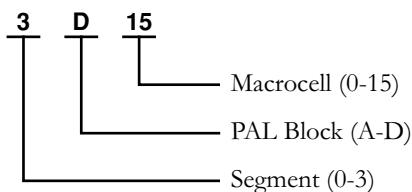
Select devices have been discontinued.
See Ordering Information section for product status.

20446G-018

Pin Designations

CLK	=	Clock
GND	=	Ground
I	=	Input
I/O	=	Input/Output
NC	=	No Connect

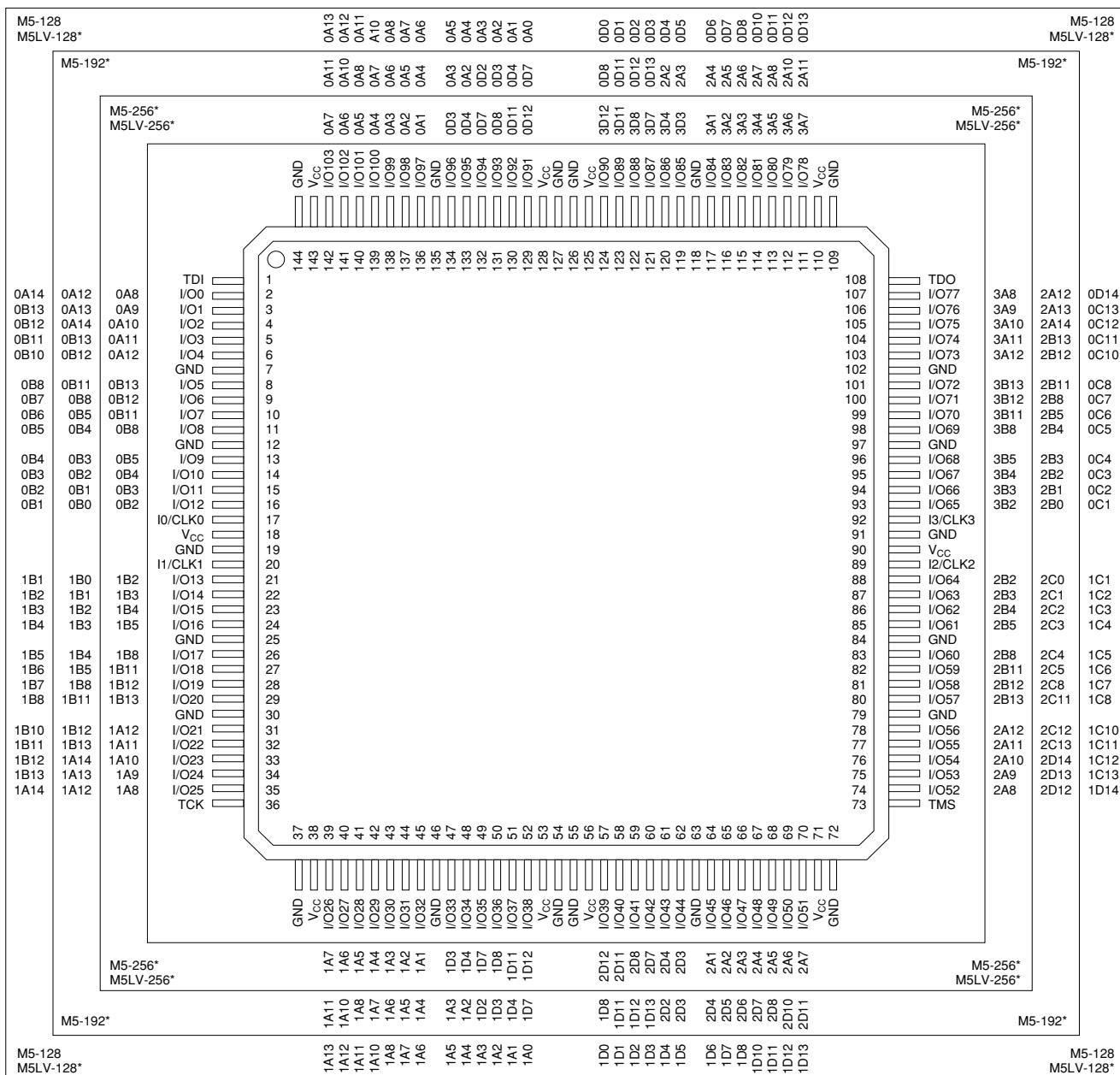
V _{CC}	=	Supply Voltage
TDI	=	Test Data In
TCK	=	Test Clock
TMS	=	Test Mode Select
TDO	=	Test Data Out



144-PIN PQFP CONNECTION DIAGRAM

Top View

144-Pin PQFP



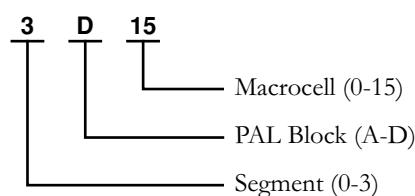
*Package obsolete, contact factory.

20446G-019

**Select devices have been discontinued.
See Ordering Information section for product status.**

Pin Designations

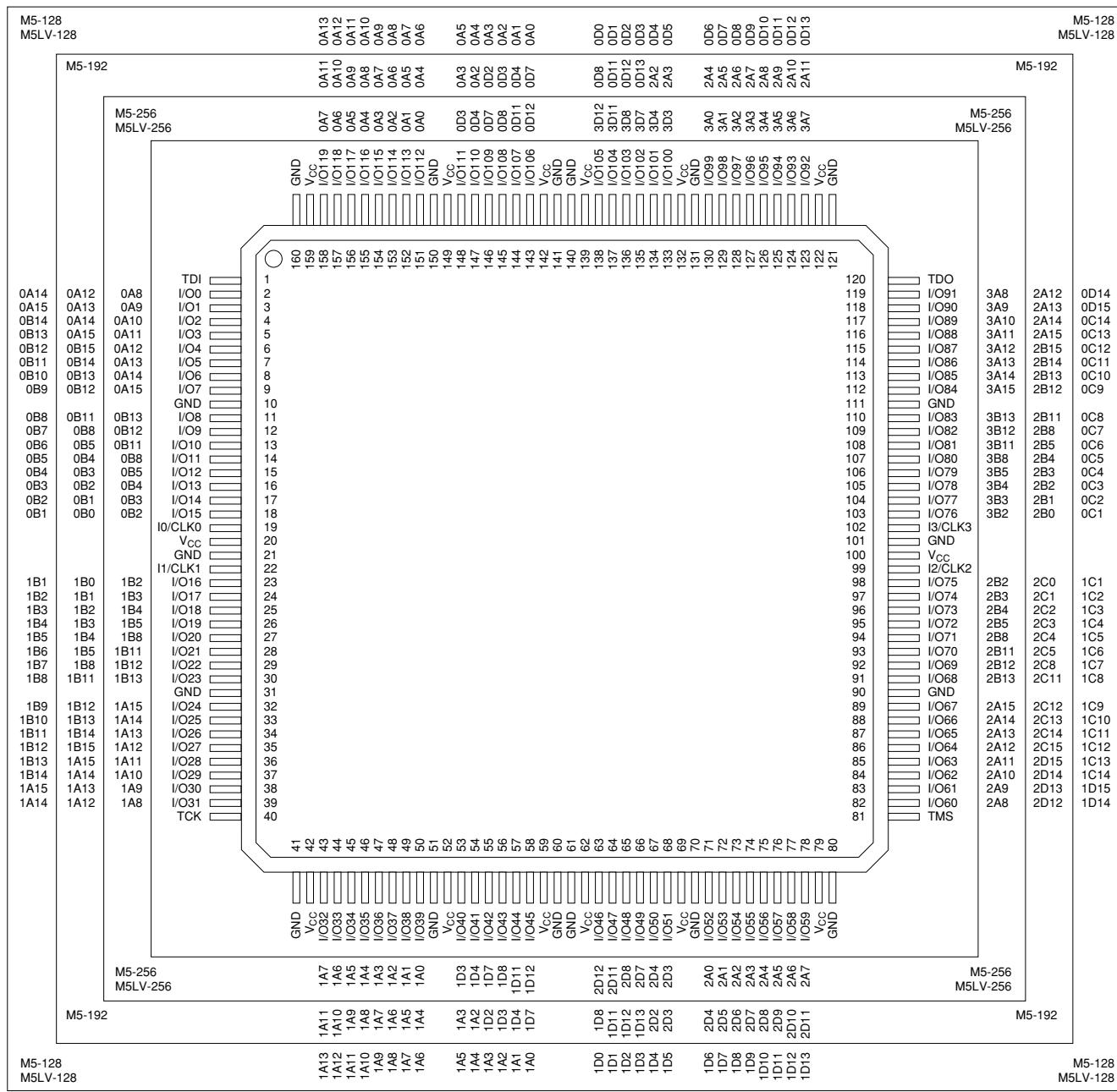
CLK	= Clock	V _{CC}	= Supply Voltage
GND	= Ground	TDI	= Test Data In
I	= Input	TCK	= Test Clock
I/O	= Input/Output	TMS	= Test Mode Select
NC	= No Connect	TDO	= Test Data Out



160-PIN PQFP CONNECTION DIAGRAM

Top View

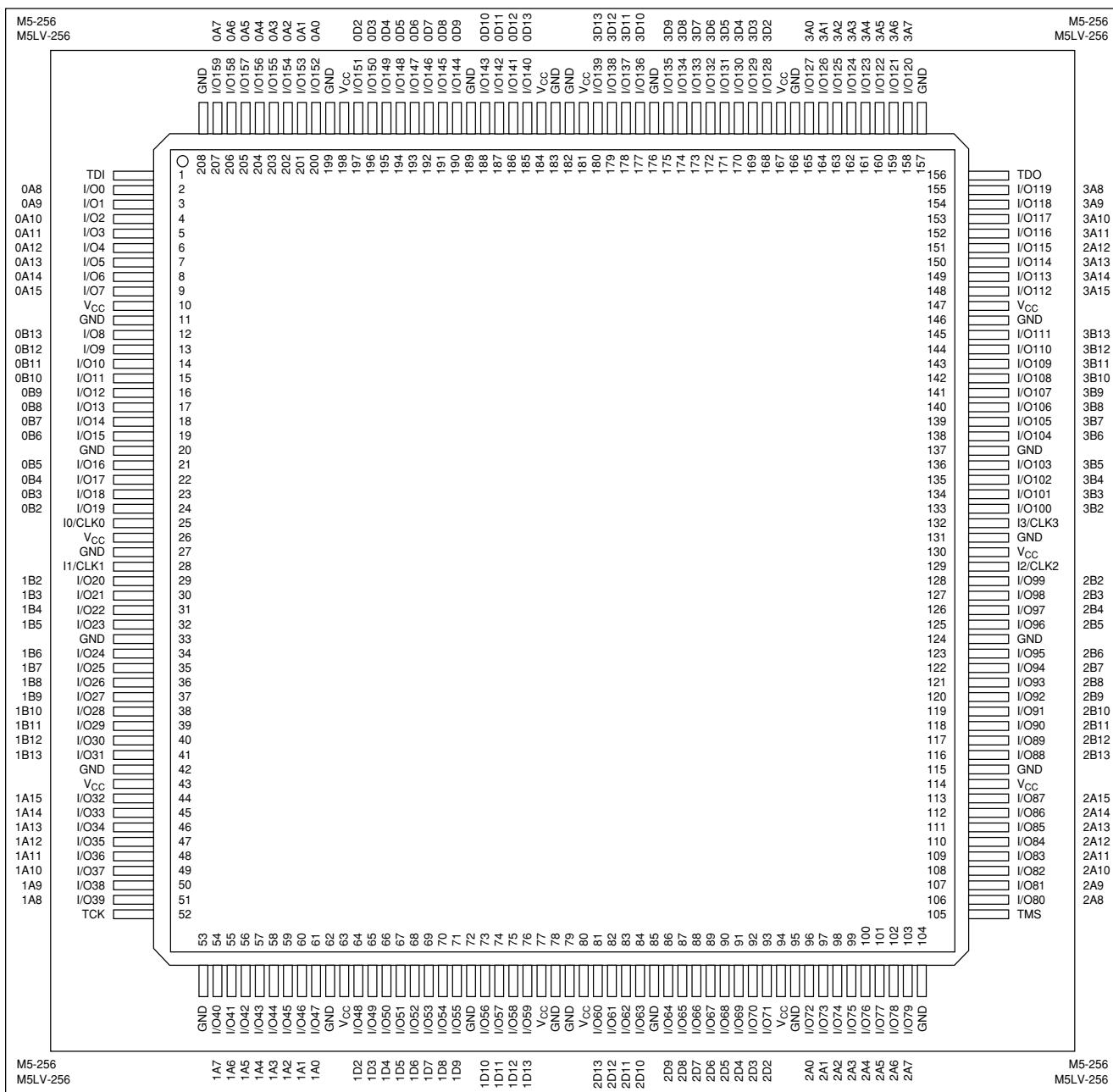
160-Pin PQFP (128, 192, 256 Macrocells)



208-PIN PQFP CONNECTION DIAGRAM

Top View

208-Pin PQFP (256 Macrocells)

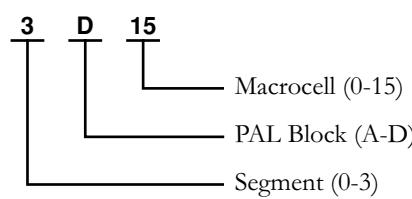


20446G-023

Select devices have been discontinued.
See Ordering Information section for product status.

Pin Designations

CLK	= Clock	V _{CC}	= Supply Voltage
GND	= Ground	TDI	= Test Data In
I	= Input	TCK	= Test Clock
I/O	= Input/Output	TMS	= Test Mode Select
NC	= No Connect	TDO	= Test Data Out



256-BALL BGA CONNECTION DIAGRAM — M5-320

Bottom View (Macrocell Association)

256-Ball BGA

	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	
A	GND	0B2	GND	0B13	4A14	GND	4A8	4A4	GND	GND	GND	4B4	4B8	GND	4B14	3B13	GND	GND	GND	A	
B	GND	0A3	0B8	0B11	4A15	4A11	4A10	4A6	4A3	4A0	4B0	4B3	4B6	4B10	4B11	4B15	3B11	3B8	3B2	GND	B
C	0D15	0A8	V _{CC}	0B3	0B4	0B12	4A13	4A9	4A5	4A1	4B1	4B5	4B9	4B13	3B12	3B4	3B3	V _{CC}	3A3	3A11	C
D	0D13	0A11	0A2	V _{CC}	V _{CC}	0B7	V _{CC}	4A12	4A7	4A2	4B2	4B7	4B12	V _{CC}	3B7	V _{CC}	3A2	3A8	3D15	D	
E	0D10	0A13	0A4	TDI												TDO	3A4	3A13	3D12	E	
F	GND	0D12	0A12	0A7												3A7	3A12	3D13	GND	F	
G	0D7	0D8	0D14	V _{CC}												V _{CC}	3D14	3D9	3D7	G	
H	GND	0D4	0D9	0D11												3D11	3D10	3D8	GND	H	
J	0D2	0D3	0D5	0D6												3D6	3D5	3D4	3D3	J	
K	GND	I/O/CLK0	0D0	0D1												3D1	3D0	I ₃ /CLK3	3D2	K	
L	1D2	I ₁ /CLK1	1D0	1D1												2D1	2D0	I ₂ /CLK2	GND	L	
M	1D3	1D4	1D5	1D6												2D6	2D5	2D3	2D2	M	
N	GND	1D8	1D10	1D11												2D11	2D9	2D4	GND	N	
P	1D7	1D9	1D14	V _{CC}												V _{CC}	2D14	2D8	2D7	P	
R	GND	1D13	1A14	1A11												2A11	2A14	2D12	GND	R	
T	1D12	1A15	1A10	TCK												TMS	2A10	2A15	2D10	T	
U	1D15	1A12	1A8	V _{CC}	V _{CC}	1A4	V _{CC}	1B3	1B8	1B13	2B13	2B8	2B3	V _{CC}	2A4	V _{CC}	2A8	2A13	2D13	U	
V	1A13	1A9	V _{CC}	1A6	1A5	1A1	1B2	1B6	1B10	1B14	2B14	2B10	2B6	2B2	2A1	2A5	2A6	V _{CC}	2A12	2D15	V
W	GND	1A7	1A3	1A2	1B0	1B4	1B5	1B9	1B12	1B15	2B15	2B12	2B9	2B5	2B4	2B0	2A2	2A3	2A9	GND	W
Y	GND	GND	GND	1A0	1B1	GND	1B7	1B11	GND	GND	2B11	2B7	GND	2B1	2A0	GND	2A7	GND	Y		
	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	

Pin Designations

- CLK = Clock
- GND = Ground
- I = Input
- I/O = Input/Output
- NC = No Connect
- V_{CC} = Supply Voltage
- TDI = Test Data In
- TCK = Test Clock
- TMS = Test Mode Select
- TDO = Test Data Out

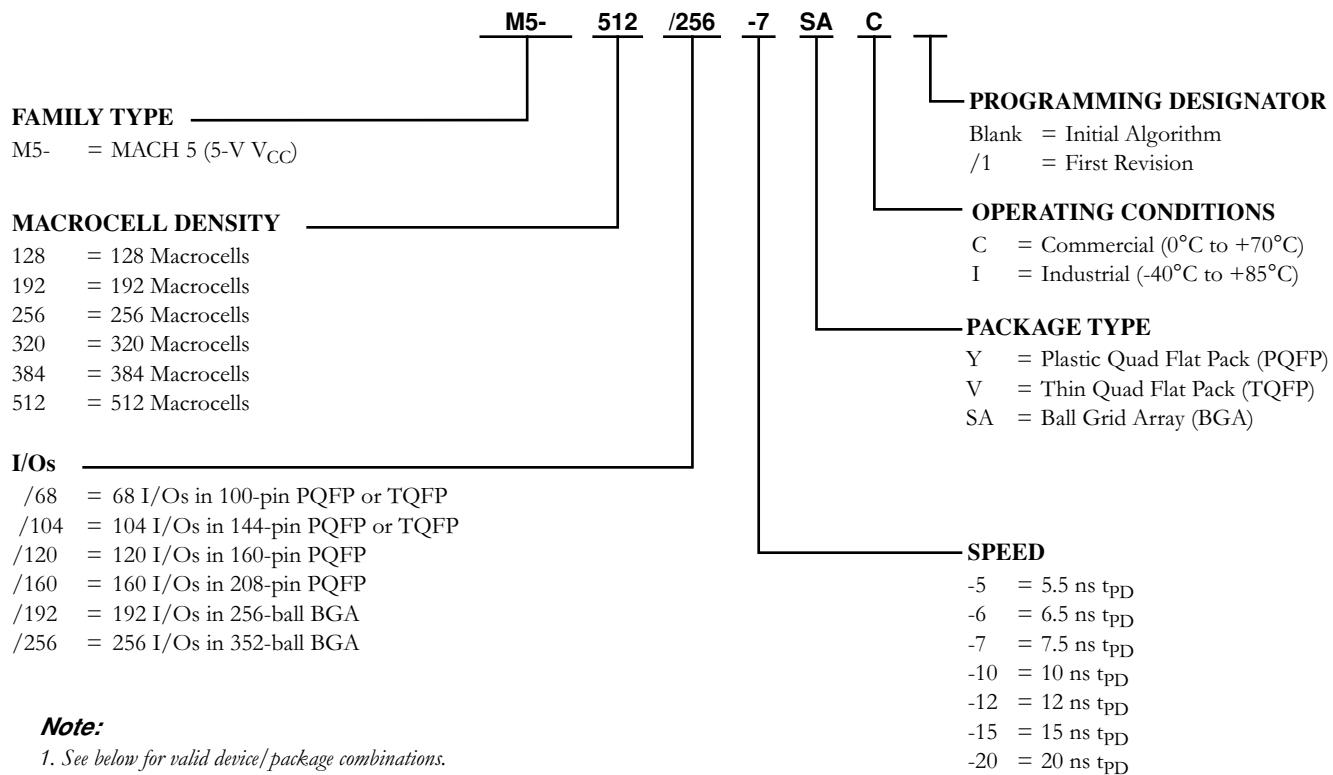
The diagram shows a grid of pins from 4 to 15. A bracket labeled "Macrocell (0-15)" covers pins 4 through 15. Another bracket labeled "PAL Block (A-D)" covers pins 4 through 15. A third bracket labeled "Segment (0-4)" covers pins 4 through 15.

Select devices have been discontinued.
See Ordering Information section for product status.

Select devices have been discontinued.
See Ordering Information section for product status.

5V M5 ORDERING INFORMATION^{1,2}

Lattice standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of the elements below.



Note:

1. See below for valid device/package combinations.
2. M5-128/1, M5-192/1 and M5-256/1 recommended for new designs.

Valid Combinations		
M5-128/68		YC, VC, YI, VI
M5-128/104		YC ¹ , YI ¹
M5-128/120	Commercial:	YC, YI
M5-192/68	-5, -7, -10, -12, -15	VC, VI
M5-192/120	Industrial:	YC, YI
M5-256/68	-7, -10, -12, -15, -20	VC, VI
M5-256/120		YC, YI
M5-256/160		YC, YI

Device Marking

Actual device marking differs from the ordering part number (OPN). All MACH devices are dual-marked with both Commercial and Industrial grades. The Industrial grade is slower, i.e., M5-512/256-7AC-10AI.

1. M5-128/104-xxYC/1 and M5-128/104-xxYI/1 have been discontinued per PCN #06-07. Contact Rochester Electronics for available inventory.

Valid Combinations		
M5-320/160	Commercial:	YC, YI
M5-320/192		SAC, SAI
M5-384/160	-6, -7, -10, -12, -15	YC, YI
M5-512/160	Industrial:	YC, YI
M5-512/256	-7, -10, -12, -15, -20	SAC, SAI

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local Lattice sales office to confirm availability of specific valid combinations and to check on newly released combinations.